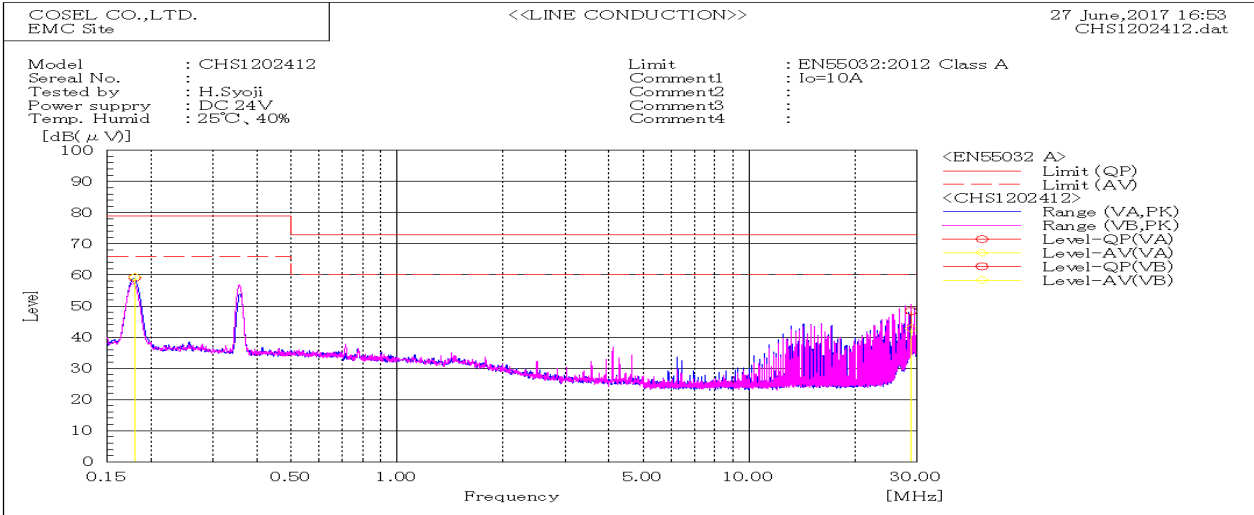
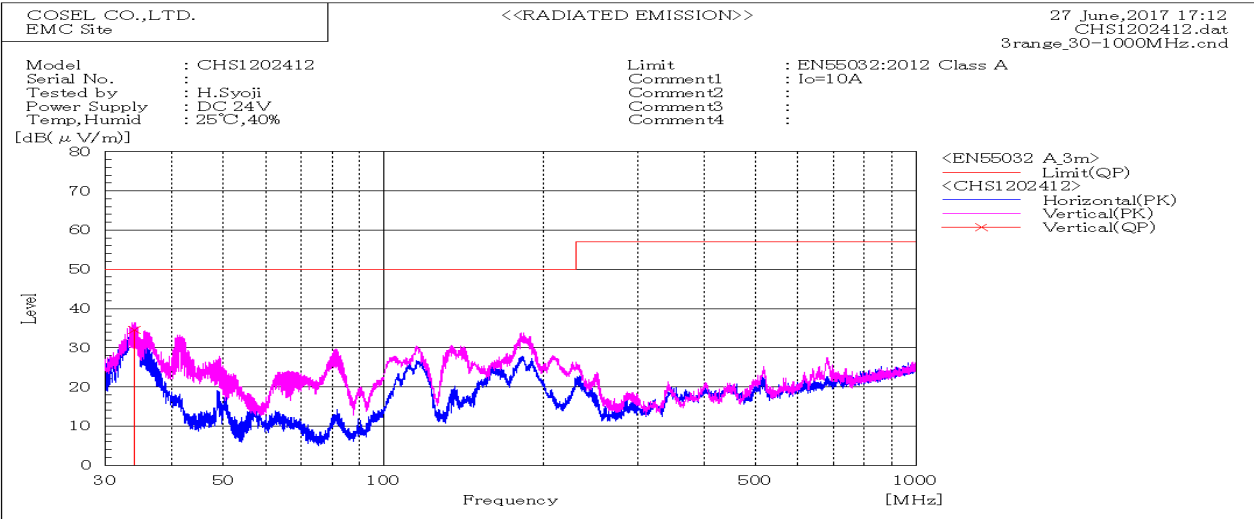


DATA SHEET		Date	27-Jun-17
Model	CHS1202412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Syoji



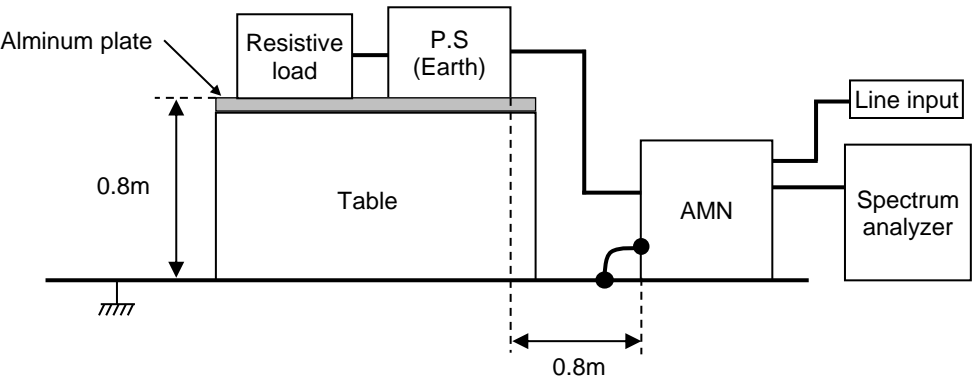
Frequency MHz	Line Phase	Level dB(μV)		Limit dB(μV)		Margin dB		Pass/Fail	Remark
		QP	AV	QP	AV	QP	AV		
0.17937	VA	59.1	59.4	79	66	19.9	6.6	Pass	
28.9446	VB	48.4	42.8	73	60	24.6	17.2	Pass	



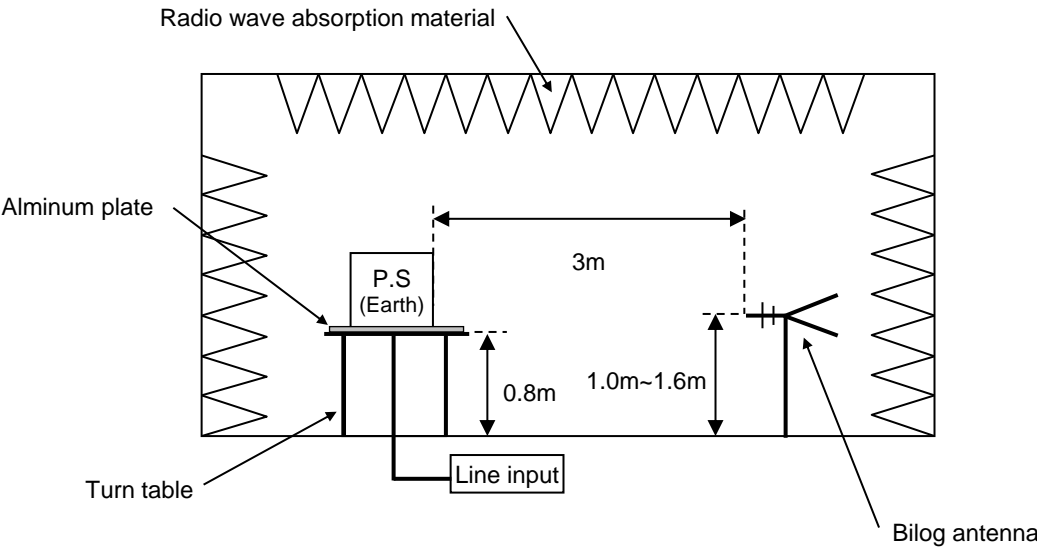
Frequency MHz	Polarization	Stability	Reading dB(μV)	Limit dB(μV/m)	Margin dB(μV/m)	Pass/Fail	Height cm	Angle deg	Remark
			QP	QP	QP				
34.059	V	Stable	34.5	50.0	15.5	Pass	157	314	

DATA SHEET		Date	27-Jun-17
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	H.Syoji

1. Line conduction



2. Radiated emission

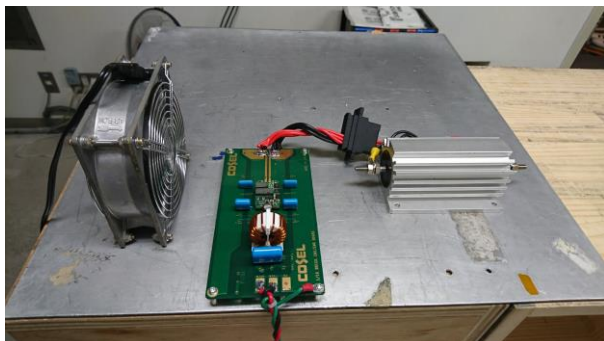


Conditions

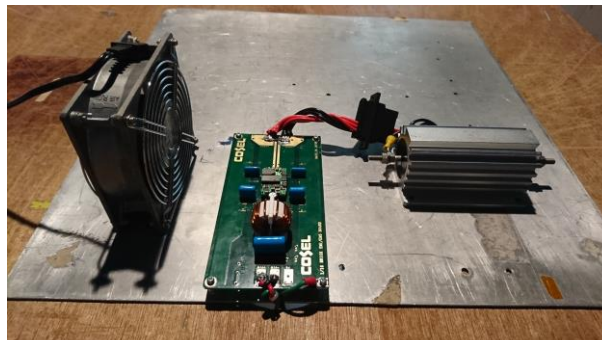
Test : EMI
Model Name : CHS12024□

○Photographs of Test Set-Up

LINE CONDUCTION



RADIATED EMISSION



○Testing circuitry

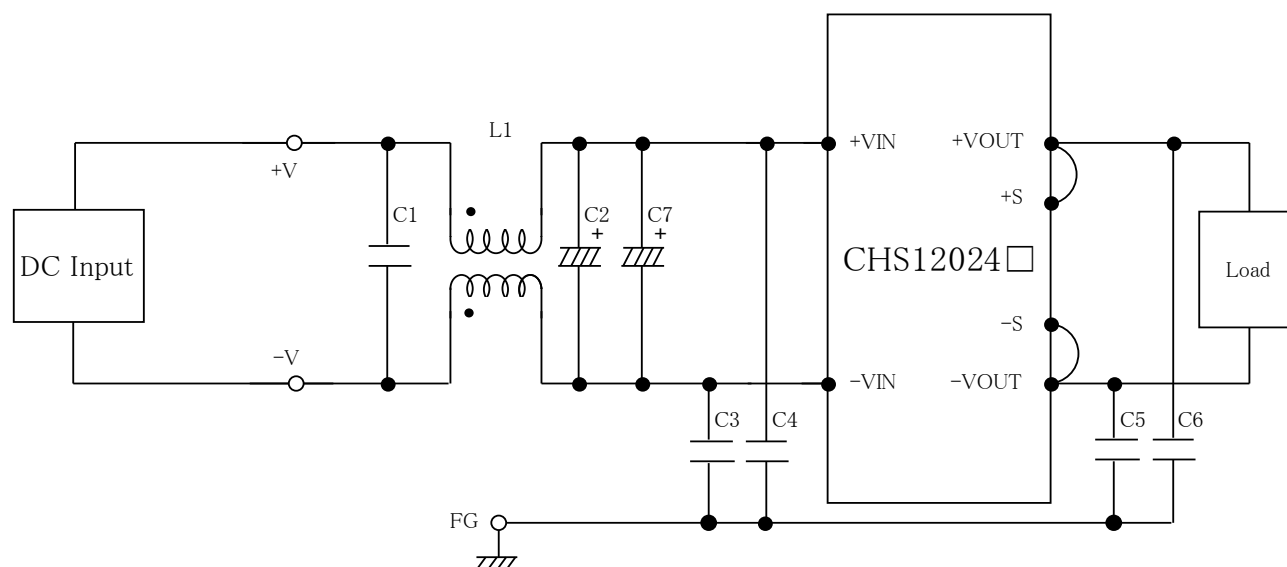


Fig.1 Testing circuitry

L1 : 0.5mH SC-15-05J (TOKIN)
C1 : 250V 2.2 μ F FPD22E225J4 (NITSUKO)
C2,C7 : 50V 100 μ F PWseries (nichicon)
C3,C4 : 630V 0.068 μ F FPD22J683J4 (NITSUKO)
C5,C6 : 630V 0.033 μ F FPD22J333J4 (NITSUKO)